

U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL. NUM 10043329	FILING DATE 01/14/2002	CLASS 430 436	SUBCLASS 22	GAU 2842	EXAMINER YOUNG
-----------------------	---------------------------	---------------------	----------------	-------------	-------------------

**APPLICANTS: Baek Kyoung-Yoon; Bae Young-Guk;

Steve Kar

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 2001-12005 03/08/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		SEC.912
Verified and Acknowledged Examiners's initials		
TITLE : Overlay key, meihod of manufacturing the same and method of measuring an overlay degree using the same		

U.S. DEPT. OF COM. / PAT. & TM. PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
Assistant Examiner		Total Claims	Print Claim for 0.9
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Figs. Drawn
Primary Examiner		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
PREPARED FOR ISSUE		<p>WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.</p>	

FILED WITH:

☐ DISK (CRF)

☐ CD-ROM

(Attached in pocket on right inside flap)